

**Search Notes**

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Examiner

Thien F. Tran

Applicant(s)/Patent under  
Reexamination

WACHI, REIKO

Art Unit

2811

**SEARCHED**

Class	Subclass	Date	Examiner
349	106, 113, 114	9/14/2006	TT
257	59, 72	9/14/2006	TT

**INTERFERENCE SEARCHED**

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**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Interference search history printout	9/14/2006	TT